

**Search Notes**

Application/Control No.

10/709,762

Examiner

Matthew G. Kayrish

Applicant(s)/Patent under  
Reexamination

HSIEH, WEI-JIA

Art Unit

2653

**SEARCHED**

Class	Subclass	Date	Examiner
369	212	12/29/2005	MK
720	646	12/29/2005	MK
292	163	1/3/2006	MK
16	441	1/3/2006	MK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
720	646	12/29/2005	MK
EAST (US-PGPUB) (See Attached Search Results)		1/10/2006	MK

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPG-PUB, USPAT, USOCR) (See Attached Search Results)	12/29/2005	MK
EAST (USPG-PUB, USPAT, USOCR) (See Attached Search Results)	1/3/2006	MK
EAST (USPG-PUB, USPAT, USOCR) (See Attached Search Results)	1/9/2006	MK
EAST (USPG-PUB, USPAT, USOCR) (See Attached Search Results)	1/10/2006 °	MK